

1. Record Nr.	UNINA9910793777703321
Autore	Rumiantsev Andrej
Titolo	On-Wafer calibration techniques enabling accurate characterization of high-performance silicon devices at the mm-wave range and beyond / / Andrej Rumiantsev
Pubbl/distr/stampa	Gistrup, Denmark ; ; Delft, Netherlands : , : River Publishers, , [2019] ©2019
ISBN	1-00-333899-2 1-003-33899-2 1-000-79285-4 87-7022-111-1
Edizione	[1st ed.]
Descrizione fisica	1 online resource (278 pages)
Collana	River publishers series in electronic materials and devices
Disciplina	621.38152
Soggetti	Semiconductors - Characterization
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Sommario/riassunto	The demand for more content, services, and security drives the development of high-speed wireless technologies, optical communication, automotive radar, imaging and sensing systems and many other mm-wave and THz applications. S-parameter measurement at mm-wave and sub-mm wave frequencies plays a crucial role in the modern IC design debug. This book presents solutions for accurate mm-wave characterization of advanced semiconductor devices. It guides through the process of development, implementation and verification of the in-situ calibration methods optimized for high-performance silicon technologies.